



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Applicant:

Ofer DU-NOUR

Serial No.: 09/762,473

Filed: February 7, 2001

**For: Method and Apparatus for Measuring the Thickness of a Transparent Film, Particularly of a Photoresist Film on a Semiconductor Substrate**

Examiner: Samuel A. Turner

Commissioner for Patents  
PO Box 1450  
Alexandria, VA 22313-1450

§ 87(2)(b)

Group Art Unit: 2877


Attorney  
Docket: **24982**  
Previously 1639/14

## FORMAL DRAWINGS

Sir:

We enclose herewith replacement formal drawings (12-sheets) for the above-identified patent application.

Respectfully submitted,

  
Sol Sheinbein

Registration No. 25,457

Date: February 18, 2004